

X-band HBT High Power Amplifier

GaAs Monolithic Microwave IC

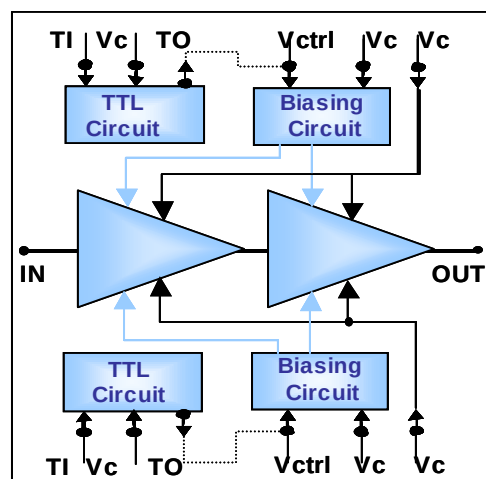
Description

The **CHA7012** chip is a monolithic two-stage GaAs high power amplifier designed for X band applications.

This device is manufactured using a GaInP HBT process, including, via holes through the substrate and air bridge. A nitride layer protects the transistors and the passive components. Special heat removal techniques are implemented to guarantee high reliability.

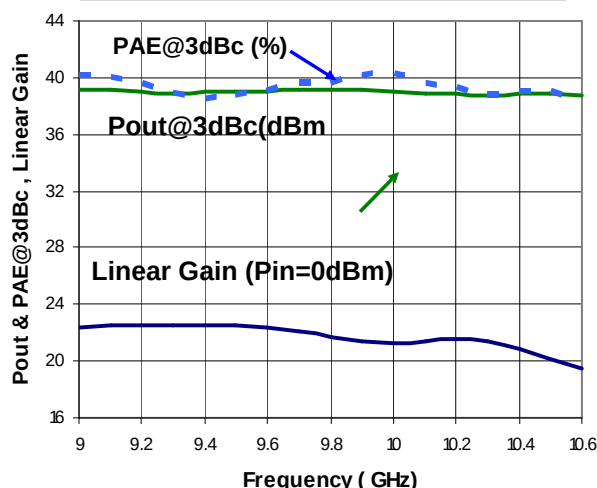
To simplify the assembly process:

- the backside of the chip is both RF and DC grounded
- bond pads and back side are gold plated for compatibility with eutectic die attach method and thermosonic or thermo compression bonding process.



Main Features

- Frequency band: 9.2 -10.4GHz
- Output power (P3dB): 38.5dBm
- High linear gain: > 20dB
- High PAE: > 38%
- Two biasing modes:
 - VDigital control thanks to TTL interface
 - VAnalog control thanks to biasing circuit
- Chip size: 5.00 x 3.68 x 0.1mm



Pout & PAE @3dBc and Linear Gain @ 25°C

Main Characteristics

Vc=7.5V, Ic (Quiescent) = 1.9A, Pulse width=100μs, Duty cycle = 20%

Symbol	Parameter	Min	Typ	Max	Unit
Fop	Operating frequency range	9.2		10.4	GHz
Psat	Saturated output power @ 25°C		9		W
P_3dBc	Output power @ 3dBc @ 25°C		7		W
G	Small signal gain @ 25°C		20		dB
Top	Operating temperature range	-40		+80	°C

ESD Protections: Electrostatic discharge sensitive device. Observe handling precautions!

Electrical Characteristics

T_{amb} = 20°C, V_c=7.5V, I_c (Quiescent) = 1.9A, Pulse width=100µs, Duty cycle = 20%

Symbol	Parameter	Min	Typ	Max	Unit
F _{op}	Operating frequency	9.2		10.4	GHz
G	Small signal gain	17.5	20	23	dB
G_T	Small signal gain variation versus temperature		-0.025		dB/°C
R _{Lin}	Input Return Loss	8	10		dB
R _{Lout}	Output Return Loss	8	12		dB
P _{sat}	Saturated output power		39.5		dBm
P _{sat_T}	Saturated output power variation versus temperature		-0.01		dB/°C
P_3dBc	Output power @ 3dBc (3)	38	38.5		dBm
PAE_3dBc	Power Added Efficiency @ 3dBc	34	38		%
V _c	Power supply voltage (3)		7.5	8	V
I _c	Power supply quiescent current (1)		1.9		A
T _I	TTL input voltage	0		5	V
I_T _I	TTL input current		1		mA
V _{ctrl}	Collector control voltage		5		V
Z _{ctr}	V _{ctrl} input port impedance (2)		350		Ohm
T _{op}	Operating temperature range	-40		+80	°C

(1) Parameter tunable by V_{ctrl} when control biasing circuit used.

(2) This value corresponds to the 4 ports in parallel (Pin 4, 8, 14, 18)

(3) 0.5V variation on V_c leads to around 0.4dB variation of the output power (impact on robustness see Maximum ratings)

Absolute Maximum Ratings (1)

T_{amb} = 20°C

Symbol	Parameter	Values	Unit
C _{mp}	Compression level (2)	6	dBc
V _c	Power supply voltage with RF	8	V
I _c	Power supply quiescent current	2.8	A
I _{c_sat}	Power supply current in saturation	3.5	A
V _{ctrl}	Collector current control voltage	6.5	V
T _j	Maximum junction temperature	175	°C
T _{stg}	Storage temperature range	-55 to +125	°C

(1) Operation of this device above any one of these parameters may cause permanent damage.

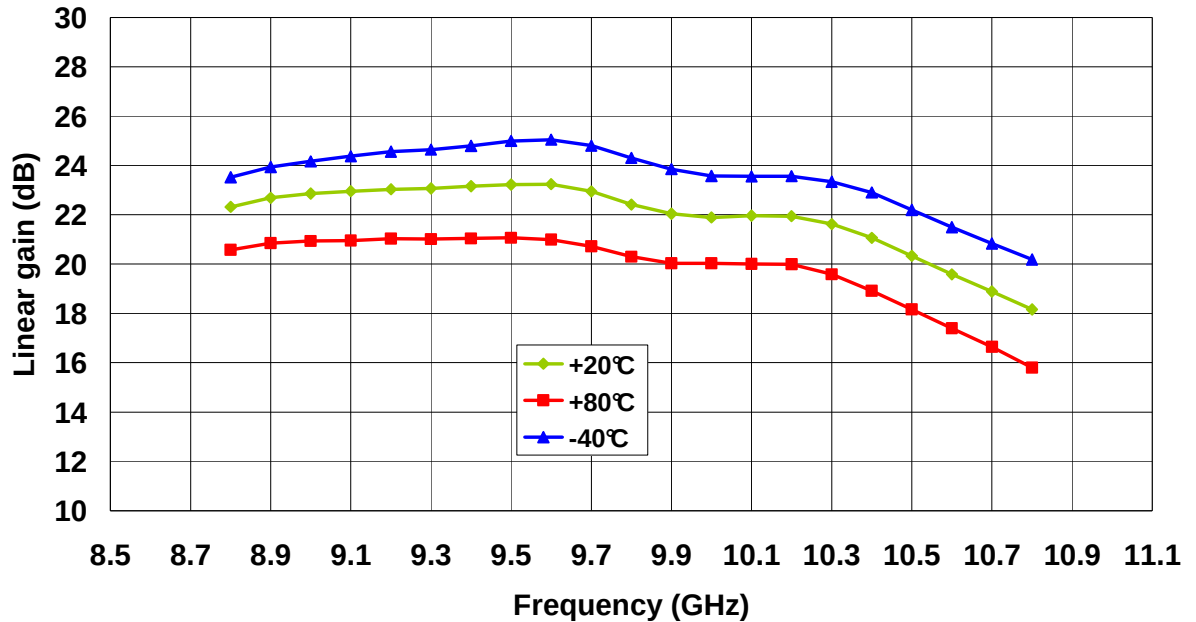
(2) For higher compression the level limit can be increased by decreasing the voltage V_c using the rate 0.5 V / dBc

Equivalent Thermal resistance to Backside: 6°C/W

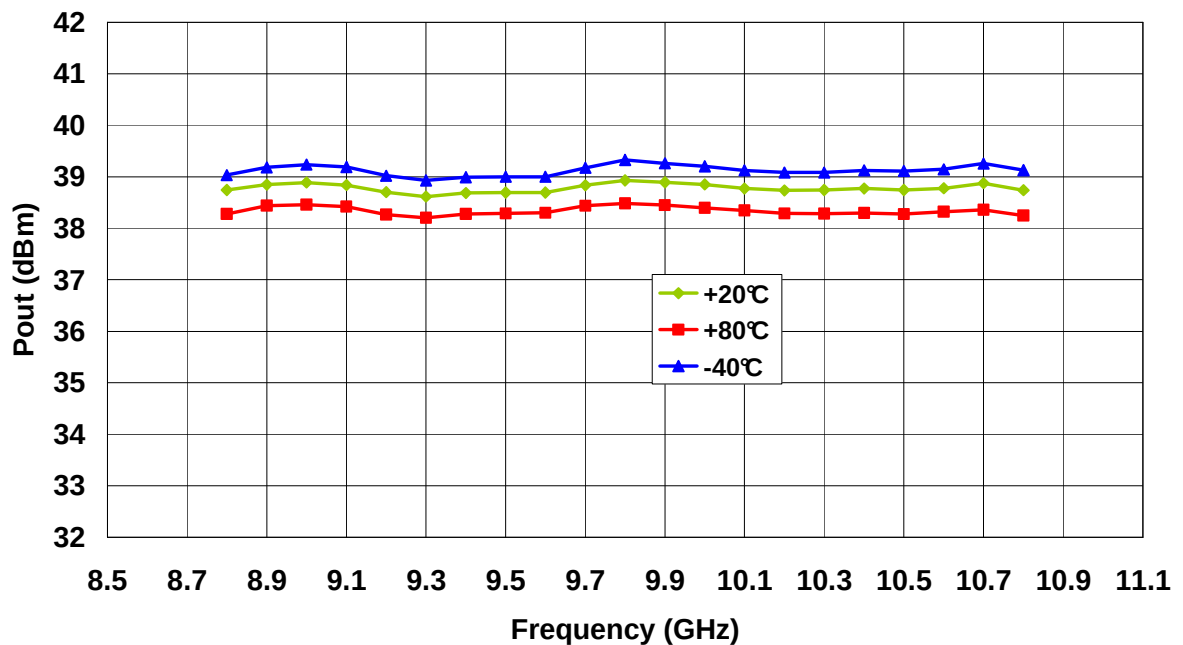
Typical measured characteristics

Measurements on Jig

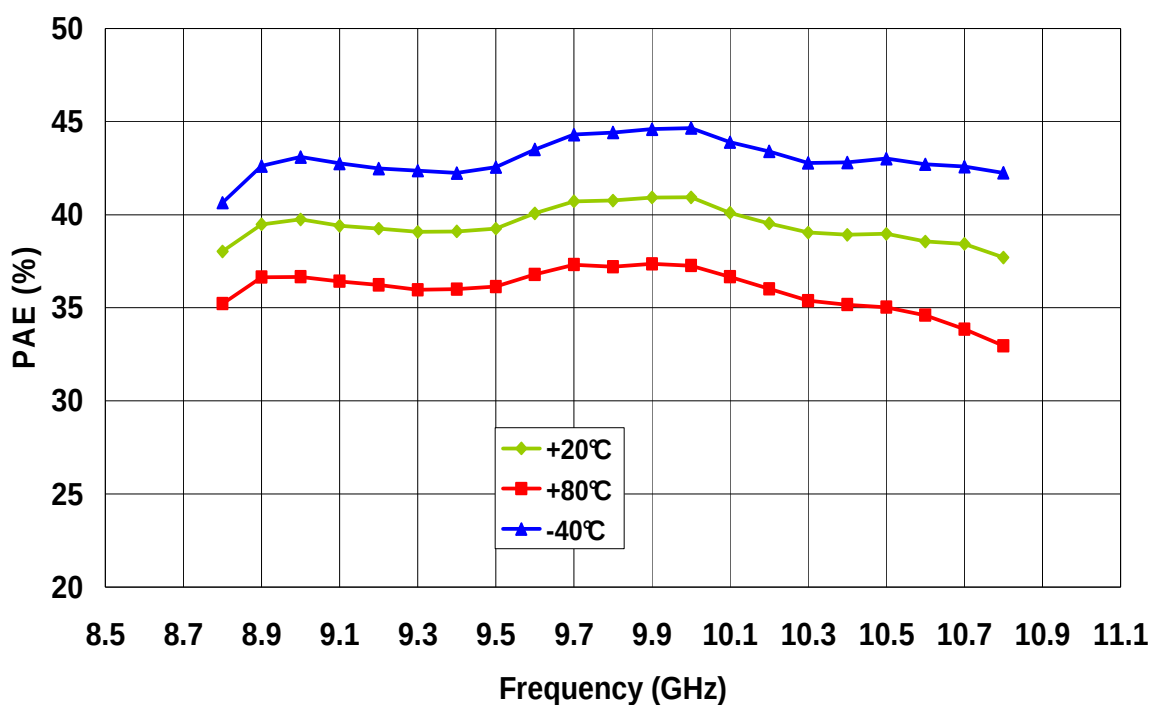
$V_c=7.5V$, $V_{TTL}=5V$, I_c (Quiescent) = 1.9A, Pulse width=100 μ s, Duty cycle = 20%



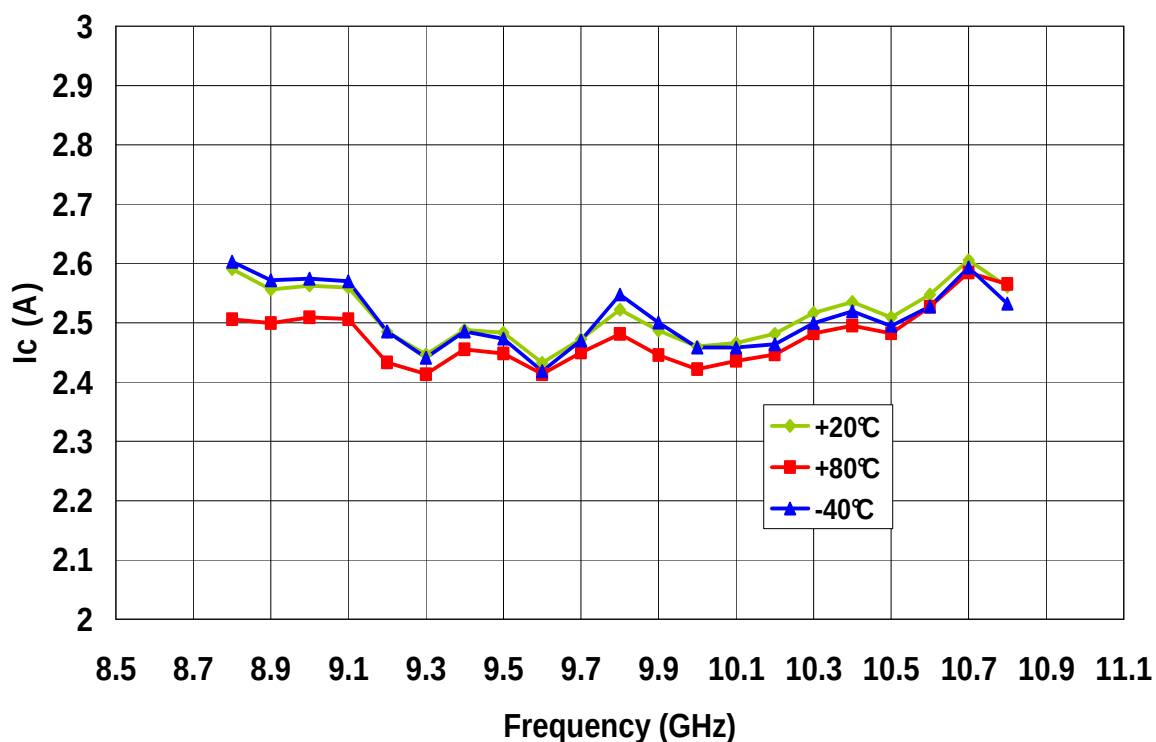
Linear gain versus frequency and temperature



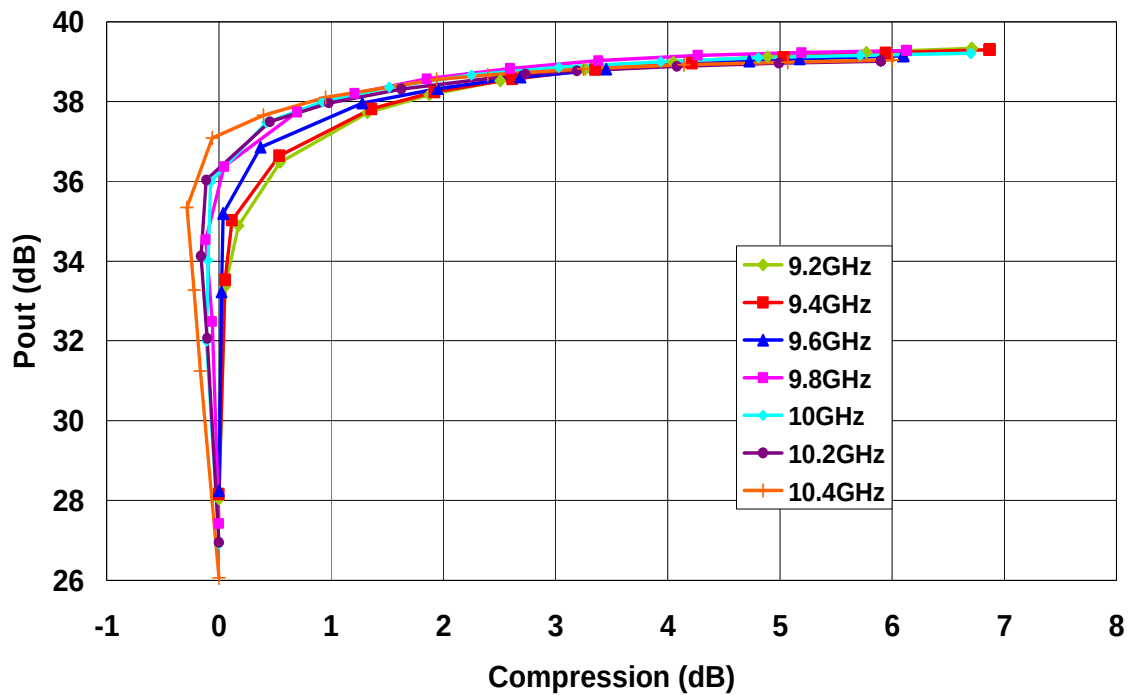
Output Power @ 3dBc versus frequency and temperature



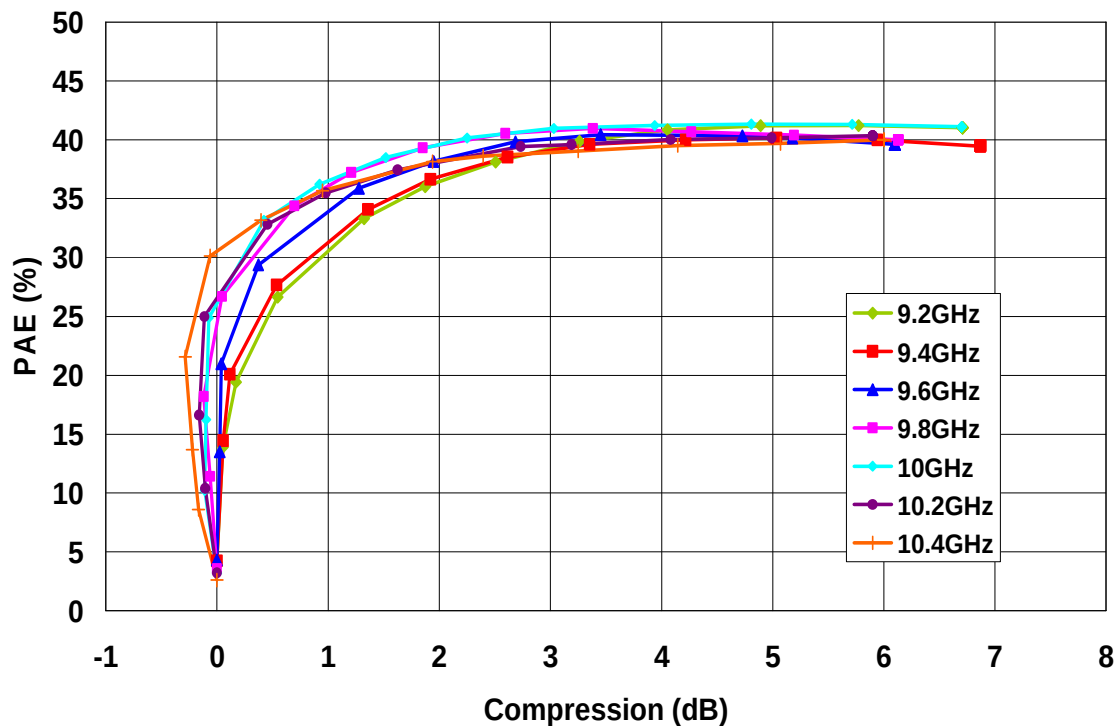
PAE @ 3dBc versus frequency and temperature



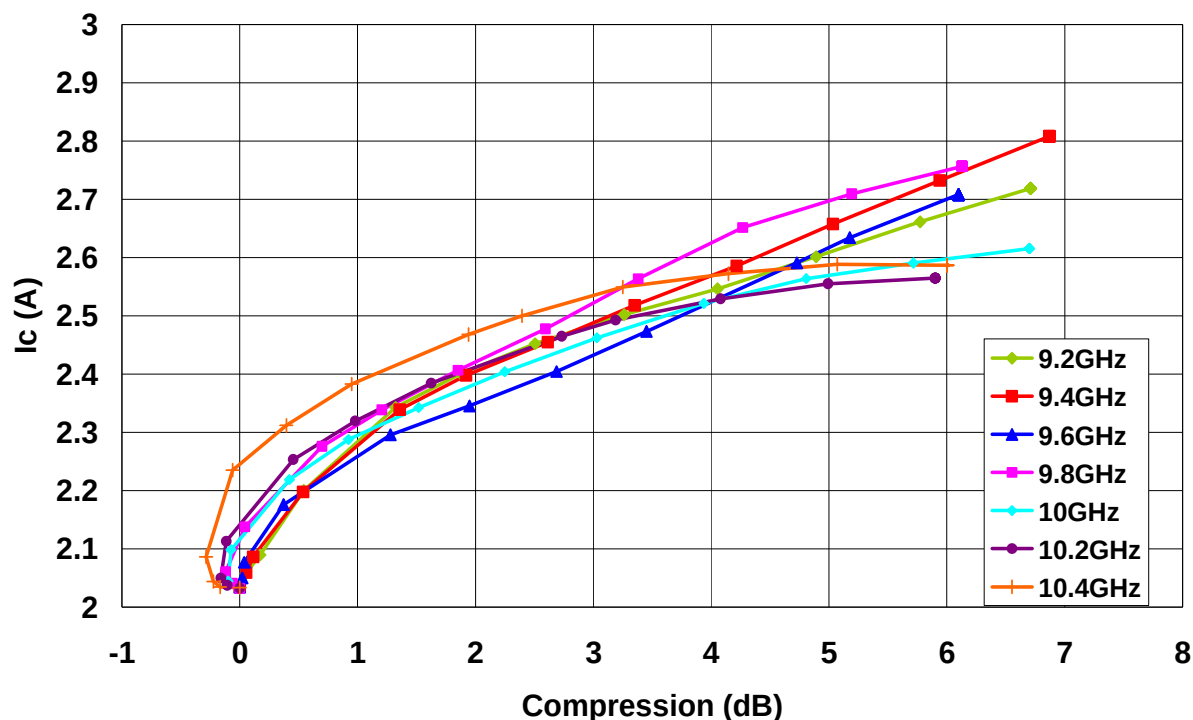
Ic @ 3dBc versus frequency and temperature



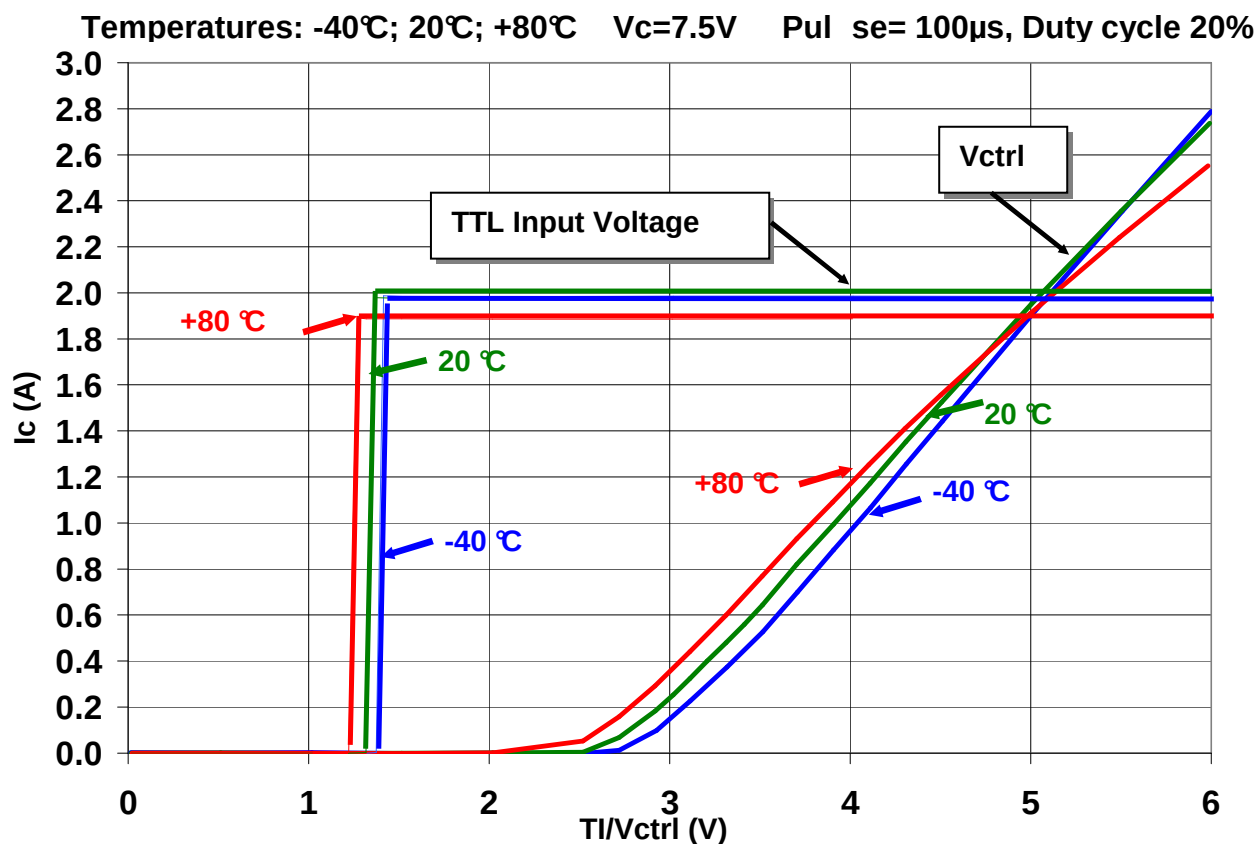
Output Power @ 25°C versus compression and frequency



PAE @ 25°C versus compression and frequency

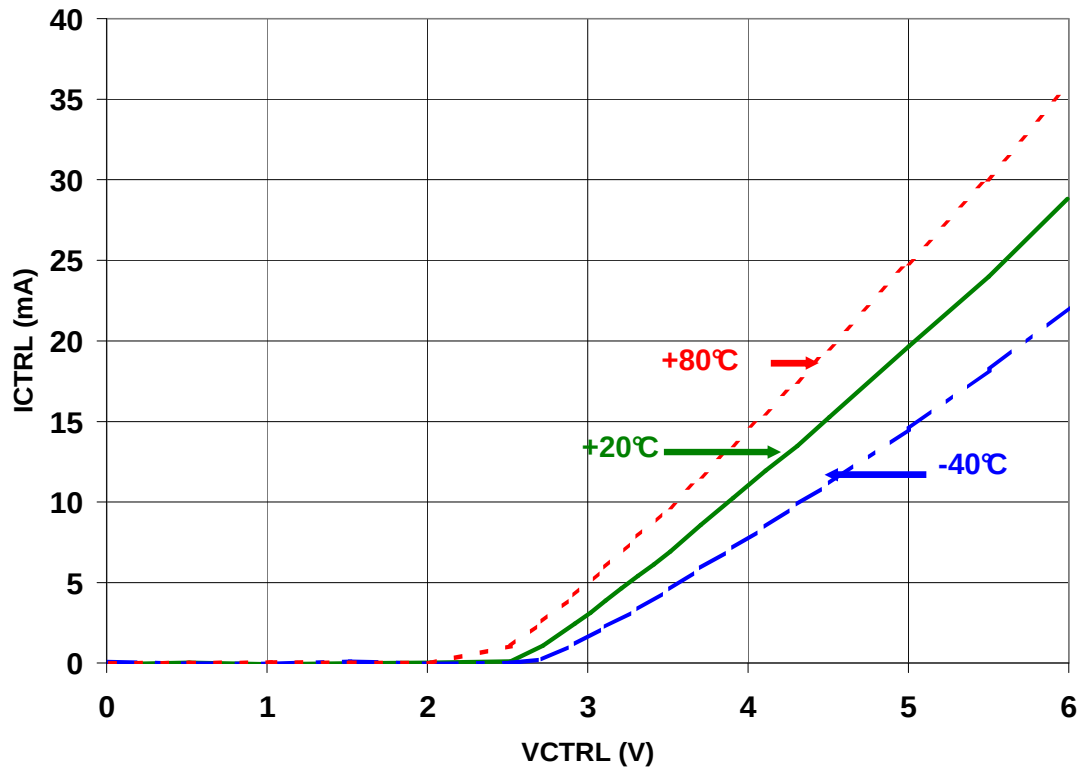


Collector current @ 25°C versus compression and frequency



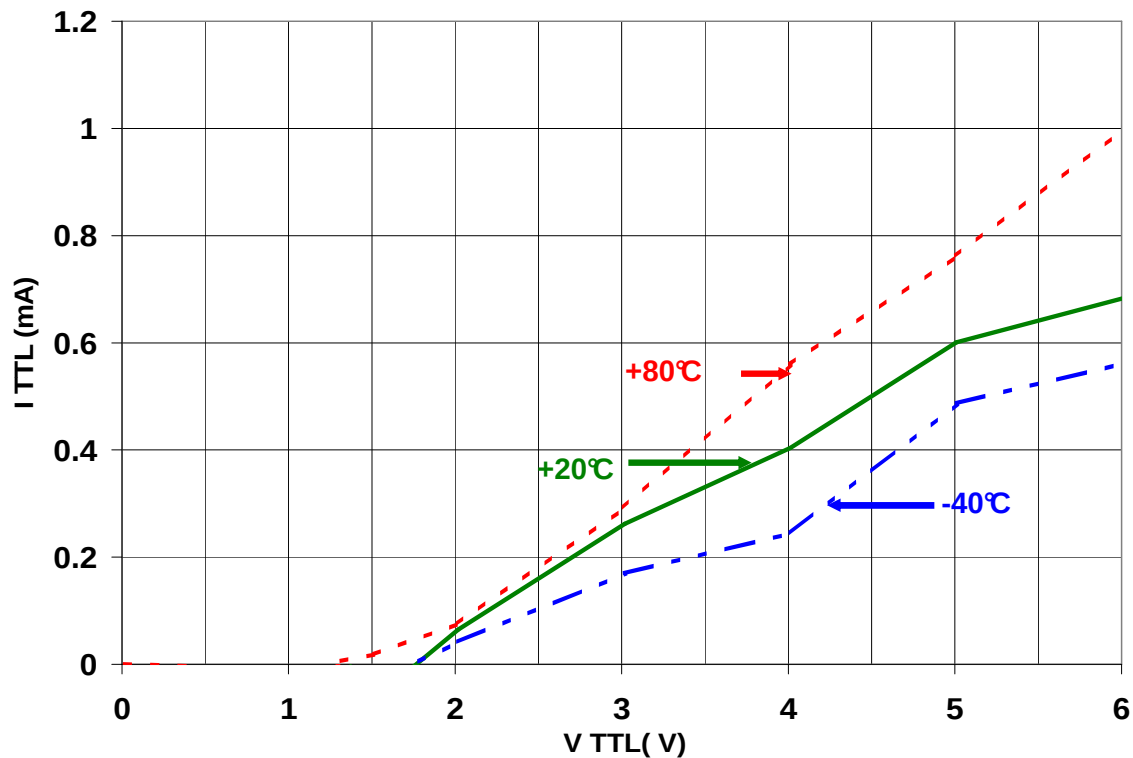
Collector quiescent current versus T_I & V_{ctrl} and temperature

Temperatures: -40°C; 20°C; +80°C $V_c=7.5V$ Pulse= 100 μs , Duty cycle 20%



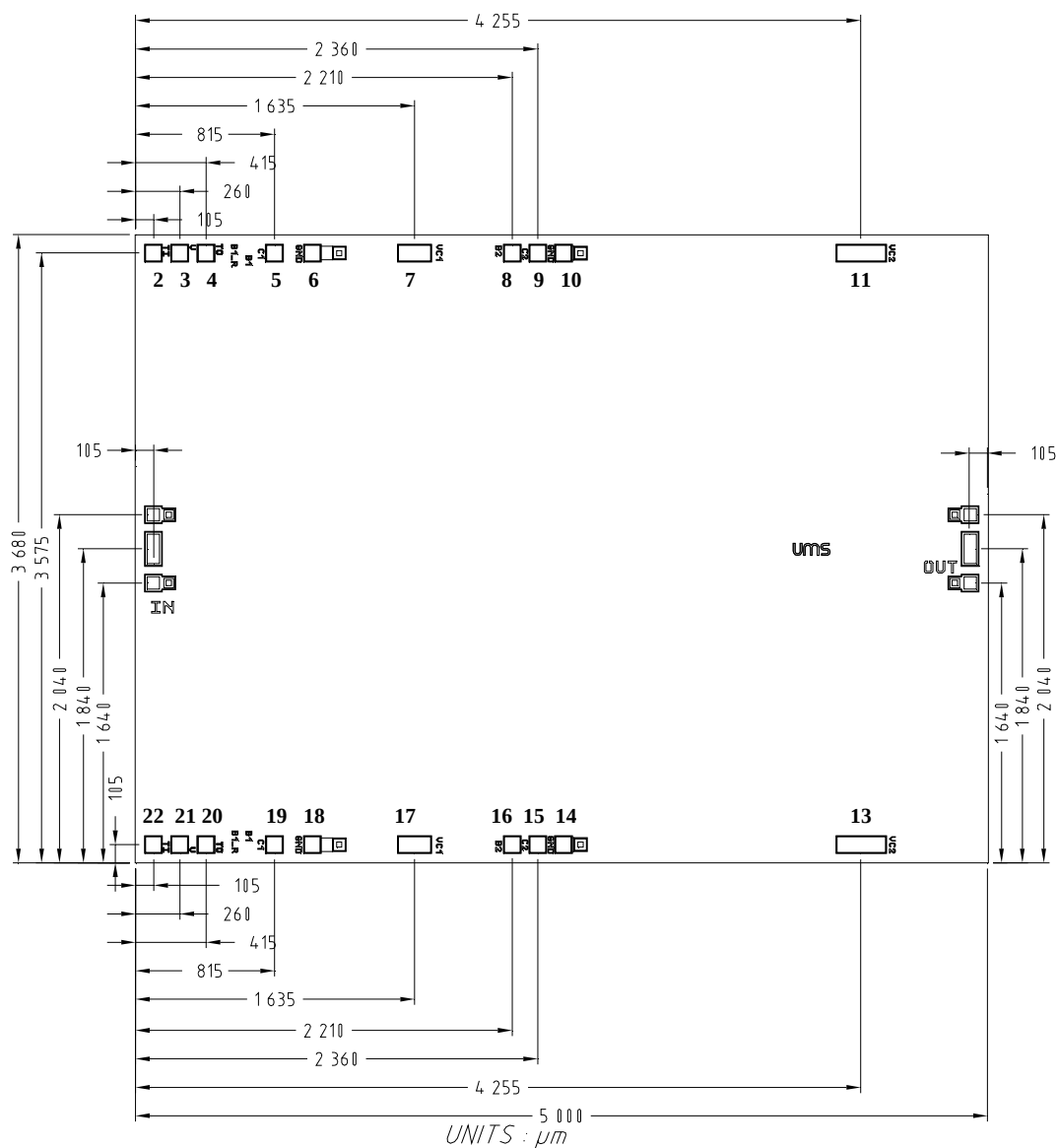
Collector current control versus control voltage and temperature

Temperatures: -40°C; 20°C; +80°C $V_c=7.5V$ Pulse= 100 μs , Duty cycle 20%



TTL input current versus TTL voltage and temperature

Chip Mechanical Data and Pin references



Chip thickness = $100\mu\text{m} \pm 10\mu\text{m}$

RF pads (1, 12) = $96 \times 196\mu\text{m}^2$

DC pads (2, 3, 4, 5, 9, 15, 19, 20, 21, 22) = $96 \times 96\mu\text{m}^2$

DC pads (7, 17) = $192 \times 96\mu\text{m}^2$

DC pads (11, 13) = $288 \times 96\mu\text{m}^2$

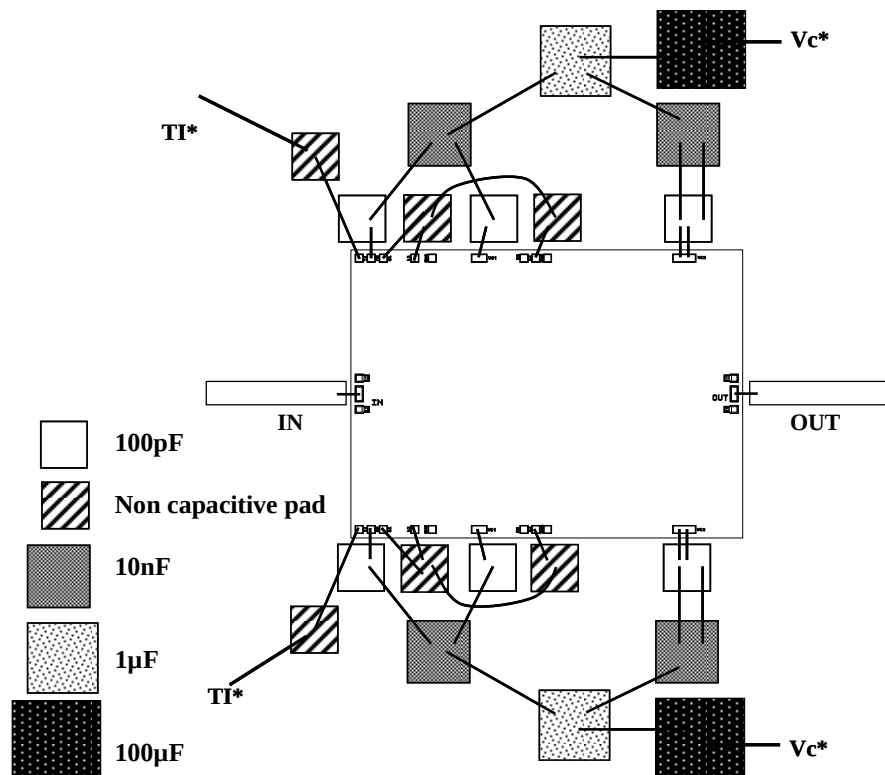
Pin number	Pin name	Description
1	IN	Input RF
8, 16		NC
5, 9, 15, 19	Vctrl	Collector current control voltage
2, 22	TI	TTL input
4, 20	TO	TTL output
6, 10, 14, 18	GND	Ground (NC)
3, 7, 11, 13, 17, 21	V,Vc1,Vc2	Power supply voltage
12	OUT	Output RF

Bonding recommendations

For thermal and electrical considerations, the chip should be brazed on a metal base plate. The RF, DC and modulation port inter-connections should be done according to the following table:

Port	Connection
IN (1)	Inductance (L_{bonding}) = 0.3nH 400 μm length with wire diameter of 25 μm
OUT (12)	Inductance (L_{bonding}) = 0.3nH 400 μm length with wire diameter of 25 μm
DC pads to 1 st decoupling level for double bonding	Inductance (L_{bonding}) = 0.7nH Two 1.2mm length wires with a diameter of 25 μm
DC pads to 1 st decoupling level for single bonding	Inductance (L_{bonding}) = 1nH One 1.2mm length wires with a diameter of 25 μm
1 st decoupling level to 2 nd decoupling level for double bonding	Inductance (L_{bonding}) = 0.7nH Two 1.2mm length wires with a diameter of 25 μm
1 st decoupling level to 2 nd decoupling level for single bonding	Inductance (L_{bonding}) = 1nH One 1.2mm length wires with a diameter of 25 μm

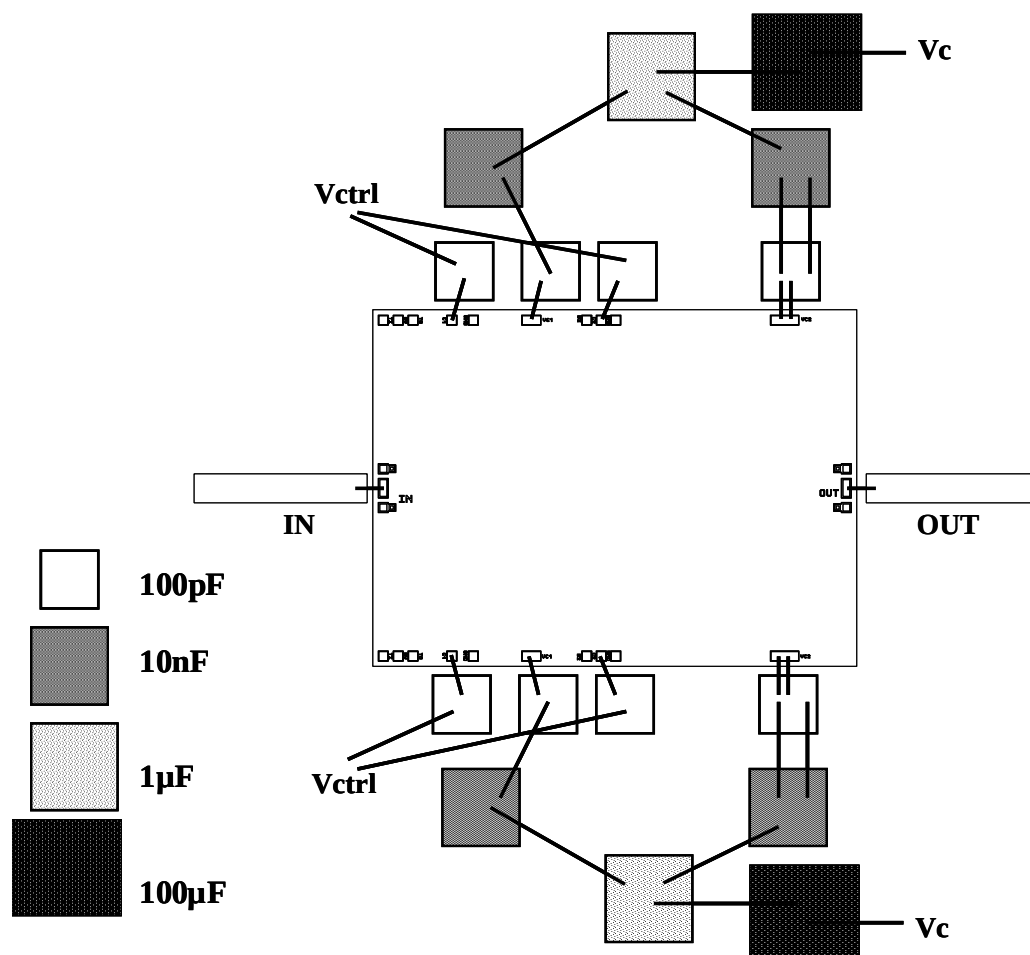
Assembly recommendations in test fixture (using TTL circuits)



* Performances obtained with the same accesses connected to the same supply

Note: Supply feed should be capacitively by-passed. 25 μm diameter gold wire is to be preferred.

Assembly recommendations in test fixture (using analog biasing circuits)



Note: Supply feed should be capacitively by-passed. 25µm diameter gold wire is to be preferred.

Ordering Information

Chip form : CHA7012-99F/00

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